## PATENT NUMBER and **ISSUE DATE**

186

	APPL NUM FILING DATE CLASS SUBCLASS GAU EXAMINER  10080831 02/21/2002 257 2844	e
	**APPLICANTS: Hino Yoshinori; Takeishi Naoei; 2815	
	**CONTINUING DATA VERIFIED:	
		100 mg
A SERVICE AND A		
	-	<b>A</b> \$
<b>多</b> 编章	** FOREIGN APPLICATIONS VERIFIED: JAPAN P 2001-053627 02/28/2001	
4 Crt. 27 1 1371	PG-PUB DO NOT PUBLISH RESCIND	4,7 -5
	Foreign priority claimed	13
	TITLE: Semiconductor device and pattern layout method thereof	)-436L(Rev. 12-94)

- 1-12	NOTICE OF ALLOWANCE MAILED		Assistant Examiner	CLAIMS ALLOWED			
SATAR A				Total Claims		nt Claim for	
學時	ISSUE FEE		The sales and the sales and the sales and the sales	DRAWING			
	Amount Due	Date Pald		Sheets Drwg.	Figs.Drwg.	Print Fig.	
		<u></u>	Primary Examiner		<u> </u>		
	TERMINAL		PREPARED FOR ISSUE	Applicati n Examiner			
	·	DISCLAMER	WARNING: The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368, Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.				
			FILED WITH: DISK	(CRF) (Attached i	n pocket on rigi	CD-ROM	